

NCE P-Channel Enhancement Mode Power MOSFET

Description

The NCE01P18K uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications. It is ESD protested.

General Features

● V_{DS} =-100V,I_D =-18A

 $R_{DS(ON)}$ <100m Ω @ V_{GS} =-10V (Typ:85m Ω)

 $R_{DS(ON)}$ <120m Ω @ V_{GS} =-10V (Typ:95m Ω)

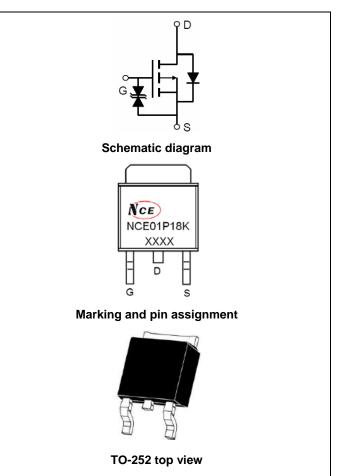
- Super high dense cell design
- Advanced trench process technology
- Reliable and rugged
- High density cell design for ultra low On-Resistance

Application

- Power management in notebook computer
- Portable equipment and battery powered systems

100% UIS TESTED!

100% ΔVds TESTED!



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
NCE01P18K	NCE01P18K	TO-252-2L	-	-	-

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	-100	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	I _D	-18	А
Drain Current-Continuous(T _C =100℃)	I _D (100℃)	-12	А
Pulsed Drain Current	I _{DM}	-100	А
Single pulse avalanche energy (Note 5)	E _{AS}	170	mJ
Maximum Power Dissipation	P _D	70	W
Derating factor		0.56	W/°C
Operating Junction and Storage Temperature Range	T_{J} , T_{STG}	-55 To 175	$^{\circ}$





Thermal Characteristic

Electrical Characteristics (T_C=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit	
Off Characteristics			•				
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =-250μA	-100	-	-	V	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-100V,V _{GS} =0V	-	-	1	μA	
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±20	μΑ	
On Characteristics (Note 3)			•				
Gate Threshold Voltage	V _{GS(th)}	$V_{DS}=V_{GS}$, $I_{D}=-250\mu A$	-1	-1.9	-3	V	
Drain Course On Chata Resistance	R _{DS(ON)}	V _{GS} =-10V, I _D =-16A	-	85	100	m0	
Drain-Source On-State Resistance		V _{GS} =-4.5V, I _D =-16A		95	120	mΩ	
Gate resistance	R _G	F=1.0MHz	-	4.5	-	Ω	
Forward Transconductance	g FS	V _{DS} =-50V,I _D =-10A	5	-	-	S	
Dynamic Characteristics (Note4)			•				
Input Capacitance	C _{lss}	., 50,414 014	-	3810	-	PF	
Output Capacitance	Coss	V_{DS} =-50V, V_{GS} =0V, F=1.0MHz	-	129	-	PF	
Reverse Transfer Capacitance	C _{rss}	F=1.UIVID2	-	125	-	PF	
Switching Characteristics (Note 4)			•				
Turn-on Delay Time	t _{d(on)}		-	16	-	nS	
Turn-on Rise Time	t _r	V _{DD} =-50V,I _D =-16A	-	73	-	nS	
Turn-Off Delay Time	t _{d(off)}	V_{GS} =-10 V , R_{GEN} =9.1 Ω	-	34	-	nS	
Turn-Off Fall Time	t _f		-	57	-	nS	
Total Gate Charge	Qg)/ F0)/ 40A	-	70	-	nC	
Gate-Source Charge	Q _{gs}	V _{DS} =-50V,I _D =-16A,	-	12.5	-	nC	
Gate-Drain Charge	Q_{gd}	V _{GS} =-10V	-	15.5	-	nC	
Drain-Source Diode Characteristics	•		•				
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =-10A	-	-	-1.2	V	
Diode Forward Current (Note 2)	Is	-	-	-	-18	Α	
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF =-16A	-	88.3	-	nS	
Reverse Recovery Charge	Qrr	di/dt = 100A/µs ^(Note3)	-	65.9	-	nC	
	1	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)					

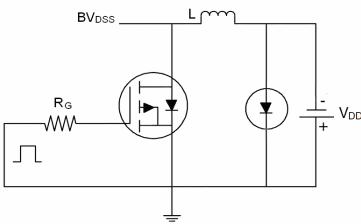
Notes:

- **1.** Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- **3.** Pulse Test: Pulse Width ≤ 300μ s, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production
- **5.** EAS condition: Tj=25 $^{\circ}$ C,V_{DD}=-50V,V_G=-10V,L=0.5mH,Rg=25 Ω

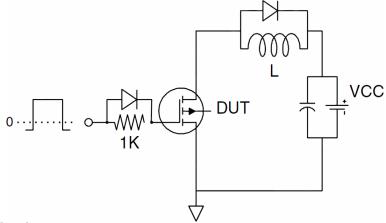


Test Circuit

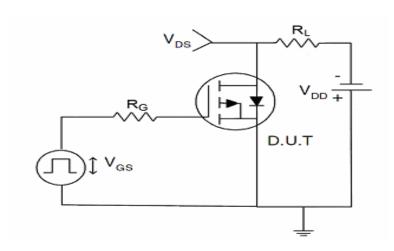
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit





Typical Electrical and Thermal Characteristics (Curves)

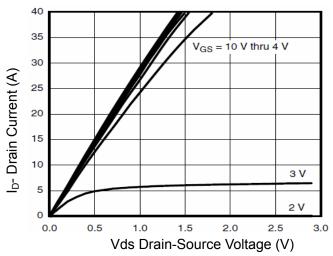


Figure 1 Output Characteristics

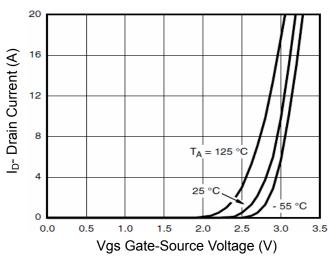


Figure 2 Transfer Characteristics

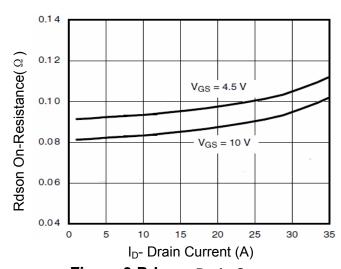


Figure 3 Rdson- Drain Current

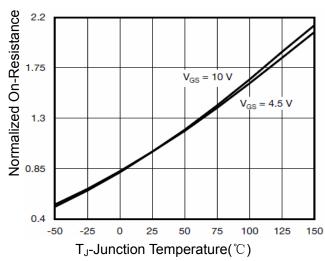


Figure 4 Rdson-JunctionTemperature

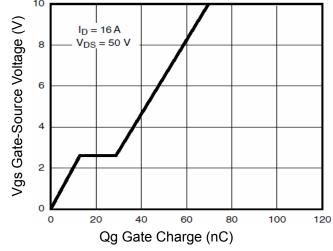


Figure 5 Gate Charge

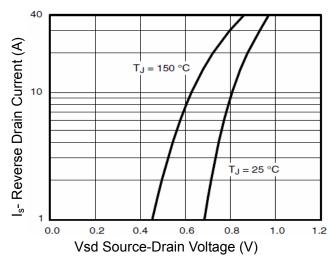


Figure 6 Source- Drain Diode Forward



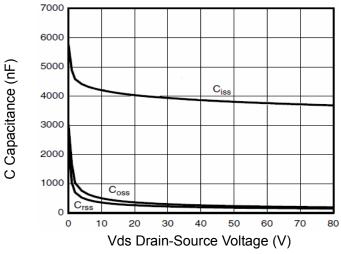


Figure 7 Capacitance vs Vds

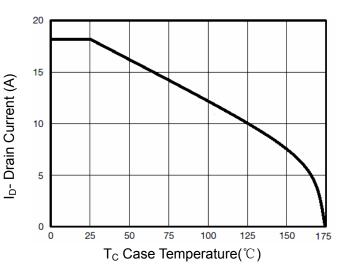


Figure 9 Drain Current vs Case Temperature

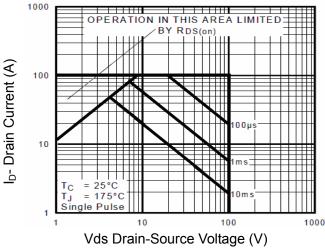


Figure 8 Safe Operation Area

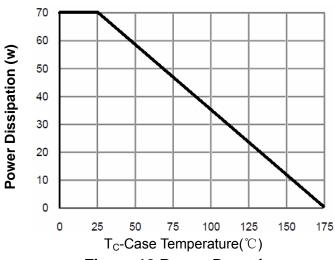


Figure 10 Power De-rating

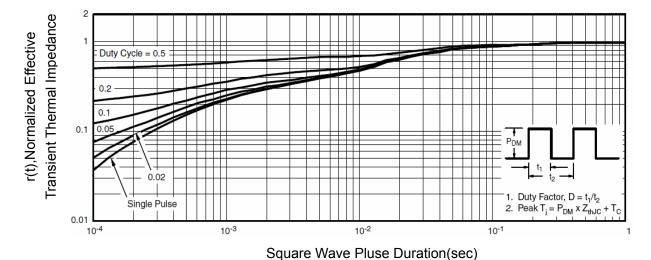
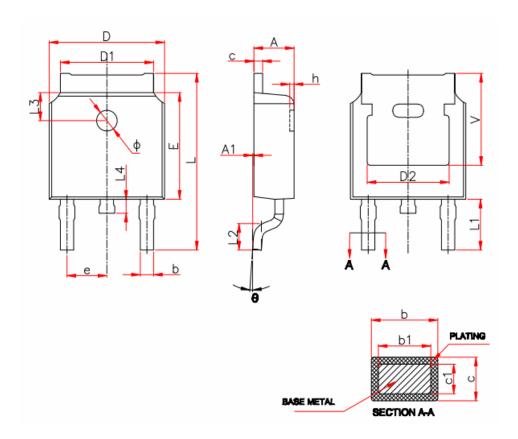


Figure 11 Normalized Maximum Transient Thermal Impedance



TO-252 Package Information



Symbol	Millimeters			
Syllibol	Min.	Max.		
Α	2.20	2.40		
A1	0.00	0.13		
b	0.66	0.86		
b1	0.73	0.79		
С	0.46	0.58		
c1	0.50	0.52		
D	6.50	6.70		
D1	5.10	5.46		
D2	4.83	REF.		
Е	6.00	6.20		
е	2.19	2.39		
L	9.80	10.40		
L1	2.90 REF.			
L2	1.40	1.70		
L3	1.60	REF.		
L4	0.60	1.00		
Ф	1.10	1.30		
θ	0°	8°		

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